## **AMENDMENTS TO THE CLAIMS**

- 1. (Previously presented) A magnetron sputtering apparatus comprising:
  - a vacuum chamber;
  - a target;
  - a cathode holding the target in the vacuum chamber;
  - a substrate;
- an anode holding the substrate and being located above the cathode so as to face the substrate toward the target on the cathode;
- a permanent magnet assembly generating a magnetic field and being located under the cathode; and
- a rotation controller rotating the permanent magnet assembly around an axis with rotation occurring on a center of the target as the axis,

the permanent magnet assembly further comprising:

- a base:
- a first permanent magnet being fixed on the base in the middle; and
- a second permanent magnet in a ring shape being fixed in a peripheral area of the base so as to surround the first permanent magnet,
- wherein a magnetic polarity of the second permanent magnet is inverse with respect to a magnetic polarity of the first permanent magnet, and
- wherein magnetic field strength of the second permanent magnet is weaker than magnetic field strength of the first permanent magnet, and
- wherein the permanent magnet assembly is formed such that a plane constituted by a top surface of the first permanent magnet and another top surface of the second permanent magnet is slanted with respect to a surface of the target.

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2. (Previously presented) The magnetron sputtering apparatus in accordance with claim 1,

wherein the first permanent magnet is fixed on a middle of the base wherein a center axis

of the first permanent magnet is shifted eccentrically with respect to the center of rotation

of the permanent magnet assembly.

3. (Previously presented) A magnetron sputtering apparatus comprising:

a vacuum chamber;

a target;

a cathode holding the target in the vacuum chamber;

a substrate;

an anode holding the substrate and being located above the cathode so as to face the

substrate toward the target on the cathode;

a permanent magnet assembly generating magnetic field and being located under the

cathode; and

a rotation controller rotating the permanent magnet assembly around an axis with

rotation occurring on a center of the target as the axis,

the permanent magnet assembly further comprising:

a base;

a first permanent magnet being fixed on a middle of the base wherein a center axis of

the first permanent magnet is shifted eccentrically with respect to the center of rotation of

the permanent magnet assembly; and

a second permanent magnet in a ring shape being fixed in a peripheral area of the base

so as to surround the first permanent magnet;

wherein a magnetic polarity of the second permanent magnet is inverse with respect to

a magnetic polarity of the first permanent magnet; and

wherein magnetic field strength of the second permanent magnet is weaker than

magnetic field strength of the first permanent magnet.

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4. (Previously presented) The magnetron sputtering apparatus in accordance with claim 1,

further comprising:

a wedge shaped member having a predetermined slant angle being located between

the rotation controller and the permanent magnet assembly; and

wherein a top surface of the member contacting a bottom surface of the base is slanted

with respect to the target.

5. (Previously presented) The magnetron sputtering apparatus in accordance with claim 2,

further comprising:

a wedge shaped member having a predetermined slant angle being located between

the rotation controller and the permanent magnet assembly; and

wherein a top surface of the member contacting a bottom surface of the base is slanted

with respect to the target.

6. (Canceled)

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